onsemi

Silicon Carbide (SiC) Combo JFET – EliteSiC, Power N-Channel, TO247-4, 750 V, 11 mohm

SiC JFET w/ Si MOSFET

UG4SC075011K4S

Description

onsemi's UG4SC075011K4S "Combo-FET" integrates both a 750 V SiC JFET and a Low Voltage Si MOSFET into a single TO247-4 Package. This innovative approach allows users to create circuitry that would enable a normally-off switch while leveraging the benefits of a normally-on SiC JFET. These benefits include ultra-low on-resistance ($R_{DS(on)}$) to minimize conduction losses and the exceptional robustness characteristic of a simplified JFET device structure, making it capable of handling the high-energy switching required in circuit protection applications. For switch-mode power conversion application, this device provides separate access to the JFET and MOSFET gates for improved speed control and ease of paralleling multiple devices.

Features

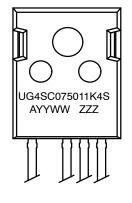
- Low R_{DS(on)}
- Normally-off Capability
- Improved Speed Control
- Improved Parallel Device Operation (3+ FETs)
- Operating Temperature: 175 °C (Max)
- High Pulse Current Capability
- Excellent Device Robustness
- Silver-sintered Die Attach for Excellent Thermal Resistance
- This Device is Pb-Free, Halogen Free and is RoHS Compliant

Typical Applications

- Solid State / Semiconductor Circuit Breaker
- Solid State / Semiconductor Relay
- Battery Disconnects
- Surge Protection
- Inrush Current Control
- High Power Switch Mode Converters (>25 kW)

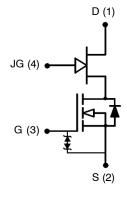


MARKING DIAGRAM



UG4SC075011K4S	= Specific Device Code
A	= Assembly Location
YY	= Year
WW	= Work Week
ZZZ	= Lot ID

PIN CONNECTIONS



ORDERING INFORMATION

See detailed ordering and shipping information on page 9 of this data sheet.

MAXIMUM RATINGS

Parameter	Symbol	Test Conditions	Value	Unit
Drain-source Voltage	V _{DS}		750	V
JFET Gate (JG) to Source Voltage	V _{JGS}	DC	-30 to +3	V
		AC (Note 1)	-30 to +30	V
MOSFET Gate (G) to Source Voltage	V _{GS}	DC	-20 to +20	V
		AC (f > 1 Hz)	-25 to +25	V
Continuous Drain Current (Note 2)	Ι _D	T _C = 25 °C	104	А
		T _C = 100 °C	75	А
Pulsed Drain Current (Note 3)	I _{DM}	T _C = 25 °C	300	А
Single Pulsed Avalanche Energy (Note 4)	E _{AS}	L = 15 mH, I _{AS} = 4.5 A	151	mJ
Power Dissipation	P _{tot}	T _C = 25 °C	357	W
Maximum Junction Temperature	T _{J,max}		175	°C
Operating and Storage Temperature	T _J , T _{STG}		–55 to 175	°C
Max. Lead Temperature for Soldering	TL		250	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. +30 V AC Rating Applies for Turn-on pulses <200 ns applied with external $R_G > 10$. 2. Limited by $T_{J,max}$ 3. Pulse width t_p limited by $T_{J,max}$ 4. Starting $T_J = 25 \text{ °C}$

THERMAL CHARACTERISTICS

Parameter	Symbol	Test Conditions	Value			
			Min	Тур	Max	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$		-	0.33	0.42	°C/W

ELECTRICAL CHARACTERISTICS (T_J = +25 °C and V_{JGS} = 0 V unless otherwise specified)

Parameter	Symbol	Test Conditi	ons	Min	Тур	Max	Unit
TYPICAL PERFORMANCE - STATIC							
Drain-source Breakdown Voltage	BV _{DS}	$V_{GS} = 0 V, V_{JGS} = 0 V,$, I _D = 1 mA	750	-	-	V
Total Drain Leakage Current	I _{DSS}	$V_{DS} = 750 \text{ V}, V_{GS} = 0^{\circ}$ $V_{JGS} = 0 \text{ V}, T_{J} = 25 ^{\circ}\text{C}$		-	3.5	60	μΑ
		$V_{DS} = 750 \text{ V}, V_{GS} = 0^{\circ}$ $V_{JGS} = 0 \text{ V}, T_{J} = 175^{\circ}$		-	45	-	
Total JFET Gate Leakage Current	I _{JGSS}	V_{JGS} = -20 V, V_{GS} = +	12 V	-	0.1	55	μΑ
Total MOSFET Gate Leakage Current	I _{GSS}	V_{GS} = -20 V / +20 V		-	2	20	μΑ
Drain-source On-resistance	R _{DS(on)}	V_{GS} = 12 V, I _D = 60 A	V _{JGS} = 2 V, T _J = 25 °C	-	10	-	mΩ
			T _J = 25 °C	-	11	14.2	
			T _J = 125 °C	-	18.4	-	
			T _J = 175 °C	-	24.2	-	
JFET Gate Threshold Voltage	V _{JG(th)}	$V_{DS} = 5 \text{ V}, \text{ V}_{GS} = 12 \text{ V}$, I _D = 85 mA	-11.3	-9.3	-6.7	V
MOSFET Gate Threshold Voltage	V _{G(th)}	$V_{DS} = 5 V, V_{JGS} = 0 V,$	I _D = 10 mA	3.5	4.5	5.5	V
JFET Gate Resistance	R _{JG}	f = 1 MHz, open drain		-	0.7	-	Ω
MOSFET Gate Resistance	R _G	f = 1 MHz, open drain		-	2.3	-	Ω

ELECTRICAL CHARACTERISTICS (T_J = +25 $^{\circ}$ C and V_{JGS} = 0 V unless otherwise specified) (continued)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
TYPICAL PERFORMANCE - REVERSE DIOL	ICAL PERFORMANCE - REVERSE DIODE					
Diode Continuous Forward Current (Note 1)	۱ _S	T _C = 25 °C	-	-	104	А
Diode Pulse Current (Note 2)	I _{S,pulse}	T _C = 25 °C	-	-	300	А
Forward Voltage	V _{FSD}	V_{GS} = 0 V, V_{JGS} = 0 V, I_S = 30 A, T_J = 25 $^\circ\text{C}$	-	1.1	1.24	V
		V_{GS} = 0 V, V_{JGS} = 0 V, I_{S} = 30 A, T_{J} = 175 °C	-	1.2	-	
Reverse Recovery Charge	Q _{rr}	$V_{DS} = 400 \text{ V}, \text{ I}_{S} = 60 \text{ A}, \text{ V}_{GS} = 0 \text{ V},$ $V_{JGS} = 0 \text{ V}, \text{ R}_{JG} = 0.7 \Omega,$	-	242	-	nC
Reverse Recovery Time	t _{rr}	di/dt = 2800 A/μs, T _J = 25 °C	-	58	-	ns
Reverse Recovery Charge	Q _{rr}	$V_{DS} = 400 \text{ V}, \text{ I}_{S} = 60 \text{ A}, \text{ V}_{GS} = 0 \text{ V},$ $V_{JGS} = 0 \text{ V}, \text{ R}_{JG} = 0.7 \Omega,$	-	280	-	nC
Reverse Recovery Time	t _{rr}	v _{JGS} = 0 v, H _{JG} = 0.7 Ω, di/dt = 2800 A/μs, T _J = 150 °C	-	89	-	ns

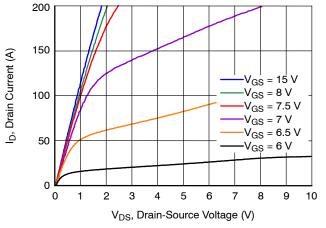
TYPICAL PERFORMANCE - DYNAMIC WITH MOSFET GATE AS CONTROL TERMINAL AND $V_{\rm JGS}$ = 0 V

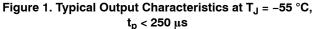
MOSFET Input Capacitance	C _{iss}	$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V},$	-	3245	-	pF
Output Capacitance	C _{oss}	V _{JGS} = 0 V, f = 100 kHz	-	178	-	
Reverse Transfer Capacitance	C _{rss}		-	1.2	-	
Effective Output Capacitance, Energy	C _{oss(er)}	$V_{DS} = 0 V \text{ to } 400 V,$	-	225	-	pF
Effective Output Capacitance, Time Related	C _{oss(tr)}	V _{GS} = 0 V, V _{JGS} = 0 V	-	470	-	pF
C _{OSS} Stored Energy	E _{oss}	V_{DS} = 400 V, V_{GS} = 0 V, V_{JGS} = 0 V	-	18	-	μJ
Total Gate Charge	Q _G	$V_{DS} = 400 \text{ V}, \text{ I}_{D} = 60 \text{ A}, \text{ V}_{JGS} = 0 \text{ V}$		75	-	nC
Gate-drain Charge	Q _{GD}	V _{GS} = 0 V to 15 V	-	13	-	
Gate-source Charge	Q _{GS}			22	-	
Turn-on Delay Time	t _{d(on)}	Notes 5 and 6 $V_{DS} = 400 \text{ V}, \text{ I}_{D} = 60 \text{ A},$ $V_{GS} = 0 \text{ V to } +15 \text{ V}, \text{ R}_{G ON} = 1 \Omega,$ $\text{R}_{G OFF} = 10 \Omega, \text{ R}_{JG ON} = 0.7 \Omega,$ $\text{R}_{JG OFF} = 4.7 \Omega,$ Inductive Load, FWD: same device with $V_{GS} = 0 \text{ V},$ $\text{R}_{JG} = 0.7 \Omega, \text{ T}_{J} = 25 \text{ °C}$	-	50	-	ns
Rise Time	t _r		-	21	-	
Turn-off Delay Time	t _{d(off)}		-	107	-	
Fall Time	t _f		-	33	-	
Turn-on Energy	E _{ON}		-	990	-	μJ
Turn-off Energy	E _{OFF}		-	513	-	
Total Switching Energy	E _{TOT}		-	1503	-	
Turn-on Delay Time	t _{d(on)}	Notes 5 and 6 $V_{DS} = 400 \text{ V}, \text{ I}_D = 60 \text{ A},$ $V_{GS} = 0 \text{ V}$ to +15 V, $R_{G_ON} = 1 \Omega$, $R_{G_OFF} = 10 \Omega$, $R_{JG_ON} = 0.7 \Omega$, $R_{JG_OFF} = 4.7 \Omega$, Inductive Load, FWD: same device with $V_{GS} = 0 \text{ V},$ $R_{JG} = 0.7 \Omega$, $T_J = 150 \text{ °C}$	-	50	-	ns
Rise Time	t _r		-	22	-	
Turn-off Delay Time	t _{d(off)}		-	110	-	
Fall Time	t _f		-	30	-	
Turn-on Energy	E _{ON}		-	986	-	Lμ
Turn-off Energy	E _{OFF}]	-	454	-	
Total Switching Energy	E _{TOT}	1	-	1440	-	

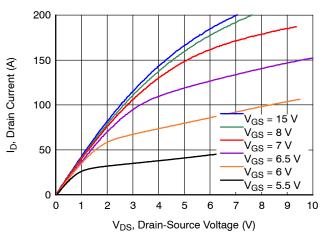
TYPICAL PERFORMANCE – DYNAMIC WITH JFET GATE AS CONTROL TERMINAL AND $V_{\mbox{GS}}$ = +12 V

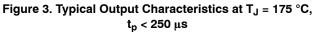
JFET Input Capacitance	C _{Jiss}	$V_{DS} = 400 \text{ V}, V_{JGS} = -20 \text{ V},$	-	1385	-	pF
JFET Output Capacitance	C _{Joss}	f = 100 kHz	-	175	-	
JFET Reverse Transfer Capacitance	C _{Jrss}		-	170	-	
JFET Total Gate Charge	Q_{JG}	V _{DS} = 400 V, I _D = 60 A, V _{JGS} = -18 V to 0 V	-	223	-	nC
JFET Gate-drain Charge	Q _{JGD}	$V_{JGS} = -18 V \text{ to } 0 V$	-	126	-	
JFET Gate-source Charge	Q _{JGS}]	-	35	_	

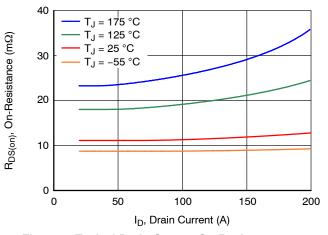
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
Measured with the half-bridge mode switching test circuit in Figure 23.
Devices are driven with the ClampDRIVE method as described in the section "Recommended Gate Drive Approach: ClampDRIVE method"

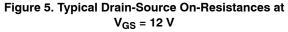


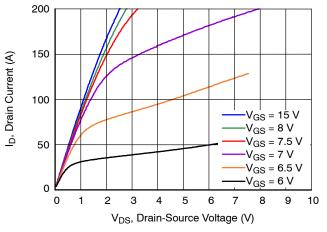


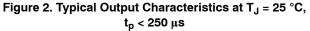












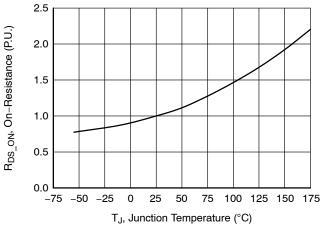
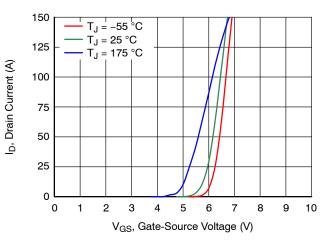
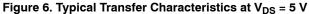
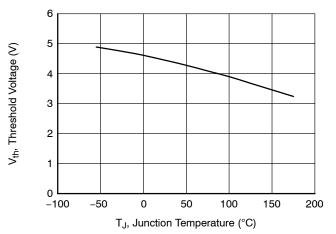


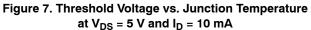
Figure 4. Normalized On-Resistance vs. Temperature at V_{GS} = 12 V and I_D = 60 A





TYPICAL PERFORMANCE DIAGRAMS – MOSFET GATE AS CONTROL TERMINAL AND $V_{JGS} = 0 V$ (continued)





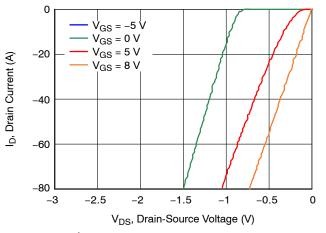


Figure 9. 3rd Quadrant Characteristics at $T_J = -55$ °C

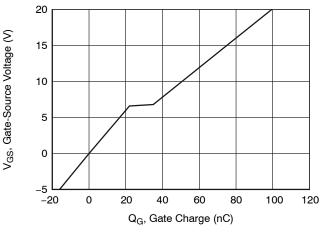


Figure 8. Typical Gate Charge at V_{DS} = 400 V and I_{D} = 60 A

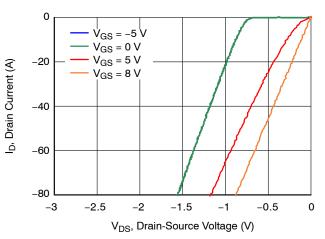


Figure 10. 3rd Quadrant Characteristics at T_J = 25 °C

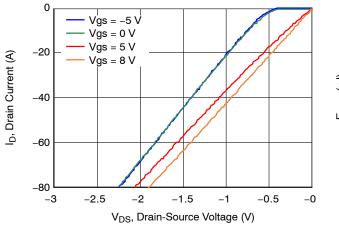


Figure 11. 3rd Quadrant Characteristics at T_J = 175 °C

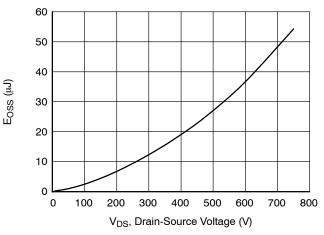
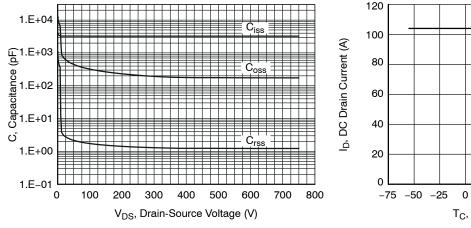
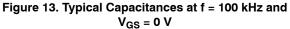
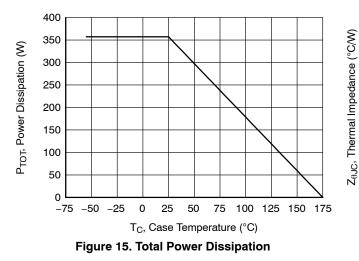


Figure 12. Typical Stored Energy in C_{OSS} at V_{GS} = 0 V

TYPICAL PERFORMANCE DIAGRAMS – MOSFET GATE AS CONTROL TERMINAL AND $V_{JGS} = 0 V$ (continued)







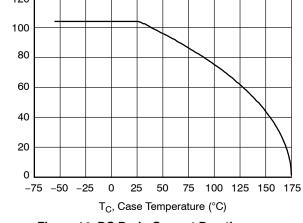


Figure 14. DC Drain Current Derating

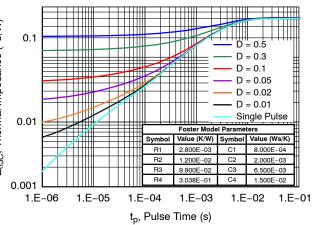
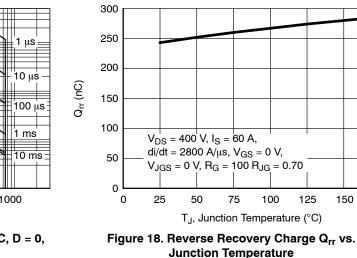
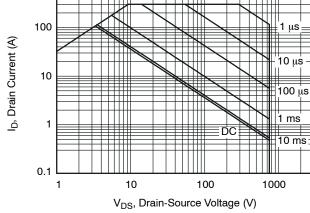


Figure 16. Maximum Transient Thermal Impedance

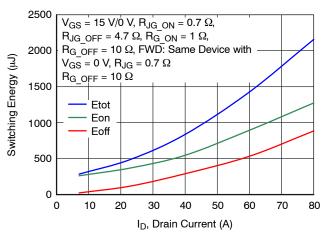
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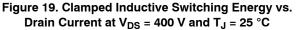


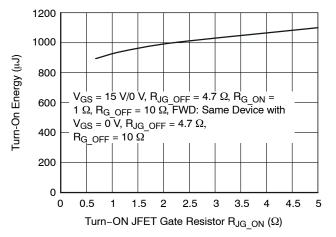


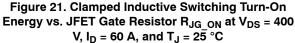


TYPICAL PERFORMANCE DIAGRAMS – MOSFET GATE AS CONTROL TERMINAL AND $V_{JGS} = 0 V$ (continued)









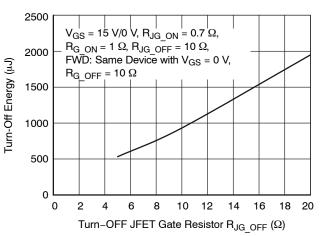


Figure 20. Clamped Inductive Turn-Off Energy vs. JFET Gate Resistor $R_{JG OFF}$ at V_{DS} = 400 V, I_D = 60 A, and $\overline{T}_{,I}$ = 25 °C

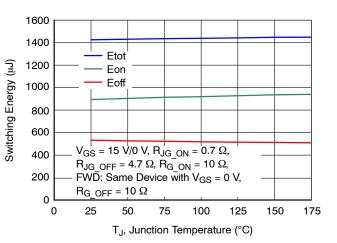
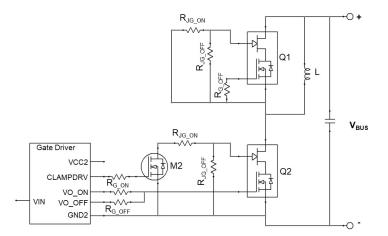
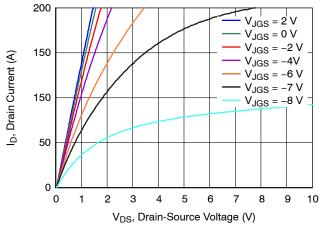
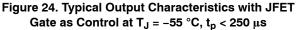


Figure 22. Clamped Inductive Switching Energy vs. Junction Temperature at V_{DS} = 400 V and I_{D} = 60 A









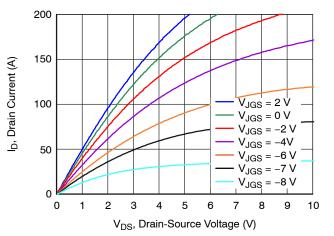


Figure 26. Typical Output Characteristics with JFET Gate as Control at T_J = 175 °C, t_p < 250 μ s

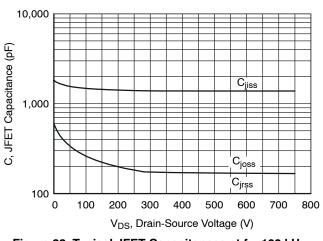


Figure 28. Typical JFET Capacitances at f = 100 kHz and V_{JGS} = –20 V

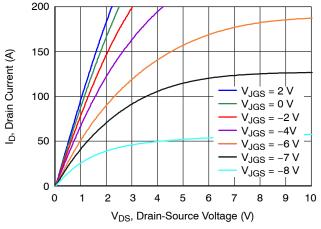


Figure 25. Typical Output Characteristics with JFET Gate as Control at T_J = 25 °C, t_p < 250 μ s

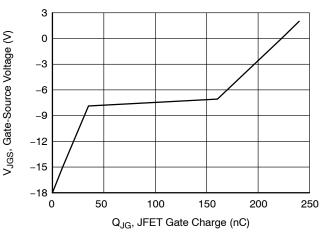


Figure 27. Typical JFET gate charge at V_{DS} = 400 V and I_D = 60 A

RECOMMENDED GATE DRIVE APPROACH: CLAMPDRIVE METHOD

Since both JFET gate and MOSFET gate are accessible, more parameters and approaches can be used to control the switching behavior of the device and make the device suitable for a wide range applications from solid state circuit breakers requiring ultra-high current turn-off capability to motor drives requiring well controlled switching speed. The recommended gate drive approach is the ClampDRIVE method, with which the desired turn-on speed, turn-off speed and reverse recovery performance can be achieved at the same time. The main idea of this method is to dynamically tune the JFET gate resistor value R_{JG} such that, in the off-state, R_{IG} is small enough not to cause a reverse recovery issue, and during turn-off transient, R_{JG} is set to a higher value for the desired turn-off performance. This method can be easily implemented using a commercial off-the-shelf gate driver with miller clamp pre-driver output, as illustrated in Figure A. VIN is the gate driver input signal. VO is the gate driver output and CLAMPDRV is the gate driver miller clamp pre-driver output. M2 is the clamp MOSFET used to control the JFET gate resistance. The MOSFET M2 is directly controlled by the CLAMPDRV signal.

In the on-state, CLAMPDRV is low which turns the MOSFET M2 off, thus, the effective JFET gate resistance is R_{JG_OFF} . During the turn-off transient, CLAMPDRV is kept low until the device is fully off. This means the JFET gate resistance is R_{JG_OFF} during the turn-off process, and R_{GJ_OFF} can be used to effectively control turn-off speed. After the device is fully off, CLAMPDRV is changed to high level, which turns the MOSFET M2 on.

In the off-state, CLAMPDRV is high and the clamp MOSFET M2 is in on-state. The effective JFET gate resistance is equal to the parallel combination of R_{JG_OFF} and R_{JG_ON} . R_{JG_ON} can be selected small enough to prevent the reverse recovery issue. During the turn-on transient, the JFET gate current may flow from the cascode source through the body diode of the MOSFET M2 and R_{JG_ON} into the JFET gate, so, the turn-on process is also determined by R_{JG_ON} .

In summary, the optimum switching performance of the SiC cascode FETs can be realized with the ClampDRIVE method by selecting proper JFET gate resistors R_{JG_ON} and R_{JG_OFF} .

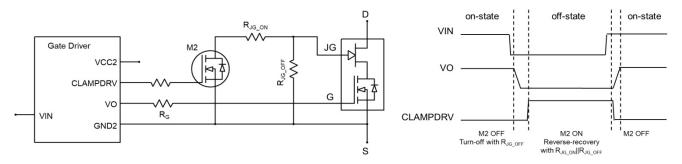


Figure 29. Circuit Schematic and Timing Diagram of the ClampDRIVE Method

ORDERING INFORMATION

Part Number	Marking	Package	Shipping
UG4SC075011K4S	UG4SC075011K4S	TO247-4 (Pb–Free, Halogen Free)	600 Units / Tube

nsemi

D2

D1

E1

MAX

5.31

2.59

2.49

1.40

2.39

0.89

21.46

1.35

16.26

_

5.20

20.32

4.50

3.80

7.39

6.20

7.19

5.62

6.17 BSC

3°

20°

10°

7.06

5.38

ØP1

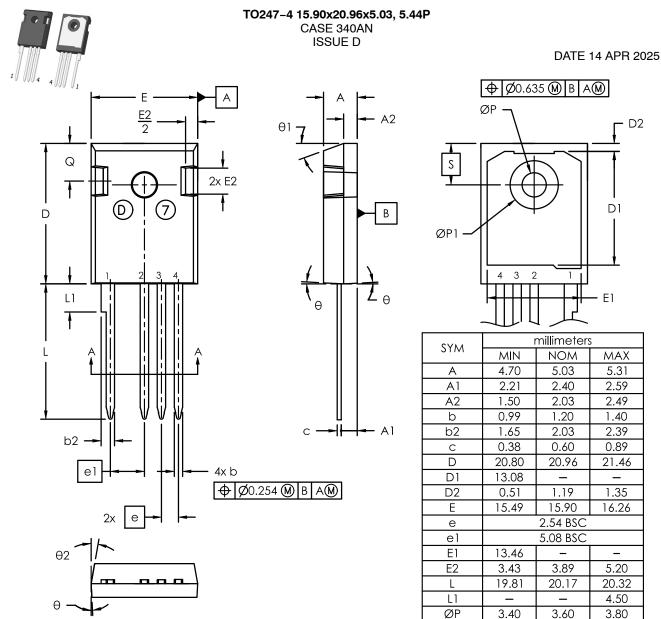
Q

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θ1

θ2



NOTE:

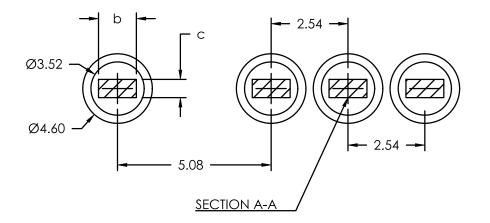
- 1. Dimensioning and tolerancing as per ASME Y14.5 2018
- 2. Controlling dimension : millimeters
- 3. Package Outline in compliance with JEDEC standard var. AD
- Dimensions D & E does not include mold flash. 4.
- ØP to have max draft angle of 1.7° to the top with max. hole 5. diameter of 3.91mm.
- 5. Through Hole diameter value = End Hole diameter
- PCB Through Hole pattern as per IPC-2221/IPC-2222 6.

DESCRIPTION: TO247-4 15.90x20.96x5.03, 5.44P PAGE 1 OF 2	DOCUMENT NUMBER:	98AON86067F	98AON86067F Electronic versions are uncontrolled except when accessed directly from the Printed versions are uncontrolled except when stamped "CONTROLLED CO		
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DATE 14 APR 2025

RECOMMENDED PCB THROUGH HOLE



NOTE: LAND PATTERN AND THROUGH HOLE DIMENSIONS SERVE ONLY AS AN INITIAL GUIDE. END-USER PCB DESIGN RULES AND TOLERANCES SHOULD ALWAYS PREVAIL.

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